

What is Tabletop SEM?

Major Features

- ▶ 3 models optimized for Basic to Advanced imaging requirements
- ▶ Fast, high quality imaging
 - Chamber evacuation time within 3 min.
 - Chamber vacuum released within 1 min.
- ▶ Simple installation and transporting
 - Setup within 30 minutes
 - Minimized installation space
- ▶ Reduced maintenance and service costs compared to full-size SEM
- ▶ Elemental Micro-Analysis using Energy Dispersive Spectroscopy (EDS) * Optional

Application

- ▶ Materials Science
 - Metals, Ceramic, Pharmaceuticals, Fibers, CNT, Battery
- ▶ Semiconductor / Electronics
- ▶ Earth Science
 - Environmental, Geology, Energy
- ▶ Life Science
 - Biomedical, Biology, Plants, Organisms, Bacteria
- ▶ Education

Performance			
Models	SNE-4500M	SNE-3200M	SNE-3000MS
Resolution	5nm	15nm	15nm
Max. "Live" Magnification	100,000x	60,000x	60,000x
Detector	SE (BSE*)	SE/BSE	SE
Vacuum	High (Low*)	High/Low	High

Specifications			
Electron Gun	Pre-centered Tungsten Filament Cartridge		
Accelerating Voltage	1 to 30kv (6 Steps - 1/5/10/15/20/30)		
Stage	5-axis (X, Y : 40mm, R-axis : 360°, Z : 0~35mm, T : 0~45°)	3-axis (X, Y : 35mm, R-axis : 360°) (Tilt Axis optional)	3-axis (X, Y : 35mm, R-axis : 360°)
Max. Sample Size	80mm(D) x 35mm(H)	70mm(D) x 30mm(H)	
Image Capture Sizes	Live scan mode : 320 x 240 Full scan mode : 640 x 450 Photo mode 1 : 1,280 x 960 Photo mode 2 : 2,560 x 1,920 Photo mode 3 : 5,120 x 3,840		
Image Format	BMP, JPEG, PNG, TIFF		
Automated Functions	Start, Focus, Stigmator, Contrast & Brightness		
Vacuum Pump	Rotary + Turbo Molecular Pump		

SNE-4500M



High Resolution Table-top SEM

The high resolving power allows real-time specimen inspection up to 100,000X. Obtaining high quality images of extremely small features or particles is made possible by utilizing the standard Variable Aperture (30, 50, 100 um) and optimal sample positioning with omnidirectional control of the 5 axis stage.

SNE-3200M



Advanced Table-top SEM

Both SE and BSE Detectors are included for SEM image analysis to enable diverse analysis for a wide variety of sample types. Both High and Low (charge reduction) Vacuum modes are standard allowing nonconductive sample analysis without metal coating.

SNE-3000MS



Entry-level Table-top SEM

The most economical model with optimized specifications for easy SEM imaging. Able to image samples within 3 minutes from exchanging samples. Optional EDS is available also at entry level prices for precise elemental micro-analysis.